



DUAL N-CHANNEL ENHANCEMENT MODE MOSFET

Product Summary

V _{(BR)DSS}	R _{DS(ON)} max	I _D max T _A = +25°C
30V	20mΩ @ V _{GS} = 10V	10A

Description

This MOSFET has been designed to minimize the on-state resistance $(R_{DS(on)})$ and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

- General Purpose Interfacing Switch
- Power Management Functions
- DC-DC Converters
- Analog Switch

Features and Benefits

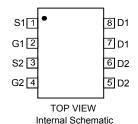
- Low On-Resistance
- Low Input Capacitance
- Low Input/Output leakage
- Low Gate Resistance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

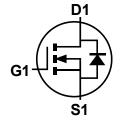
Mechanical Data

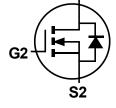
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See diagram
- Terminals: Finish NiPdAu over Copper leadframe. Solderable per MIL-STD-202, Method 208
- Weight: 0.072 grams (approximate)











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N-Channel MOSFET

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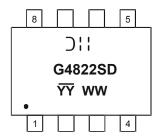
Ordering Information (Note 4)

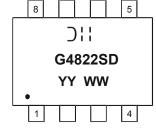
Part Number	Case	Packaging
DMG4822SSD-13	SO-8	2,500/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information





Shanghai A/T Site

);; = Manufacturer's Marking
G4822SD = Product Type Marking Code
YYWW = Date Code Marking
YY or YY = Year (ex: 13 = 2013)
WW = Week (01 - 53)
YY = Date Code Marking for SAT (Shape

 $\frac{\text{YY}}{\text{YY}}$ = Date Code Marking for SAT (Shanghai Assembly/ Test site) $\frac{\text{YY}}{\text{YY}}$ = Date Code Marking for CAT (Chengdu Assembly/ Test site)



Maximum Ratings @TA = 25°C unless otherwise specified

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	±25	V
Continuous Drain Current (Note 5) V _{GS} = 10V	Steady State	T _A = +25°C T _A = +85°C	I _D	10 6.6	Α
Pulsed Drain Current (Note 6)			I _{DM}	60	А
Avalanche Current (Note 7 & 8)			I _{AR}	1.68	Α
Repetitive Avalanche Energy L= 0.3mH (Note 7 & 8)			E _{AR}	12.8	mJ

Thermal Characteristics @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 5)	P _D	1.42	W
Thermal Resistance, Junction to Ambient (Note 5)	$R_{\theta JA}$	88.4	°C/W
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C

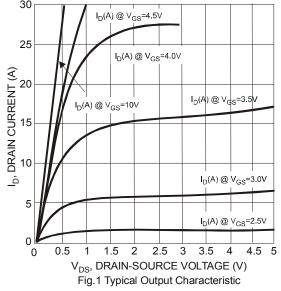
Electrical Characteristics @TA = 25°C unless otherwise specified

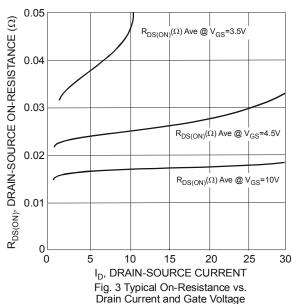
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Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 9)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	-	-	V	$V_{GS} = 0V$, $I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	-	-	1	μA	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	-	-	±100	nA	$V_{GS} = \pm 25V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 9)							
Gate Threshold Voltage	V _{GS(th)}	1	-	3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	D	-	13.4	20	mΩ	$V_{GS} = 10V, I_D = 8.5A$	
Static Dialii-Source Off-Resistance	R _{DS (ON)}	-	19.5	31	11152	$V_{GS} = 4.5V, I_D = 6A$	
Forward Transfer Admittance	Y _{fs}	-	20	-	mS	$V_{DS} = 5V, I_{D} = 8.5A$	
Diode Forward Voltage	V_{SD}	-	0.4	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 10)	_						
Input Capacitance	C _{iss}	-	478.9	-	pF		
Output Capacitance	Coss	-	96.7	-	pF	│V _{DS} = 16V, V _{GS} = 0V, │f = 1MHz	
Reverse Transfer Capacitance	C _{rss}	-	61.4	-	pF		
Gate resistance	Rg		1.1		Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Q_g		5	-	nC	V _{GS} = 10V, V _{DS} = 15V, I _D =8.5A	
Total Gate Charge (V _{GS} = 10V)	Q_{g}	-	10.5	-	nC		
Gate-Source Charge	Q_{gs}	-	1.8	-	nC		
Gate-Drain Charge	Q_{gd}	-	1.6	-	nC		
Turn-On Delay Time	t _{D(on)}	-	2.9	-	ns		
Turn-On Rise Time	t _r	-	7.9	-	ns	V _{DS} = 15V, V _{GS} = 10V,	
Turn-Off Delay Time	t _{D(off)}	-	14.6	-	ns	$R_L = 1.8\Omega, R_G = 3\Omega,$	
Turn-Off Fall Time	t _f	-	3.1	-	ns		

Notes:

- 5. Device mounted on FR-4 PCB, with minimum recommended pad layout.
- 6. Device mounted on minimum recommended pad layout test board, 10µs pulse duty cycle = 1%
- $\label{eq:continuous} \textbf{7. Repetitive rating, pulse width limited by junction temperature.}$
- 8. I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep T_i=+25°C
- 9. Short duration pulse test used to minimize self-heating effect.
- 10. Guaranteed by design. Not subject to product testing.







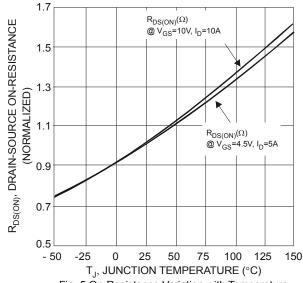
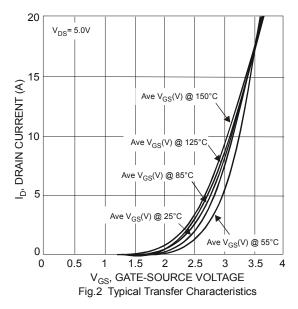
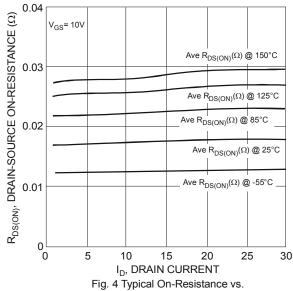


Fig. 5 On-Resistance Variation with Temperature





Drain Current and Temperature

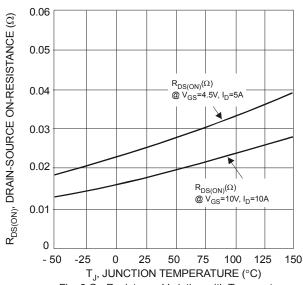
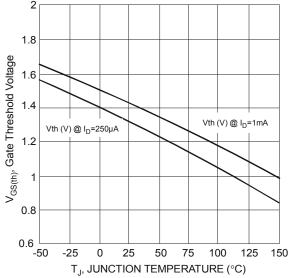
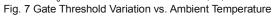


Fig. 6 On-Resistance Variation with Temperature









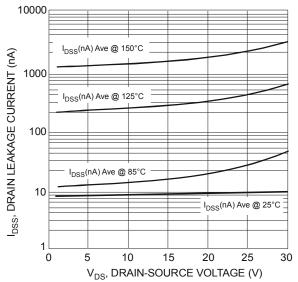
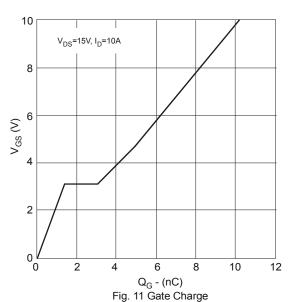


Fig. 9 Typical Drain-Source Leakage Current vs. Voltage



20 18 16 I_S, SOURCE CURRENT (V) 14 12 10 8 $V_{SD}(V)@T_A=25$ °C 6 2 0 0.2 0.3 0.4 0.5 0.6 0.7 0.8 0.9 1.1 1.2 V_{SD}, SOURCE-DRAIN VOLTAGE (V) Fig.8 Diode Forward Voltage vs. Current

1000 Ciss Ave(pF) - Crss Ave(pF) - C



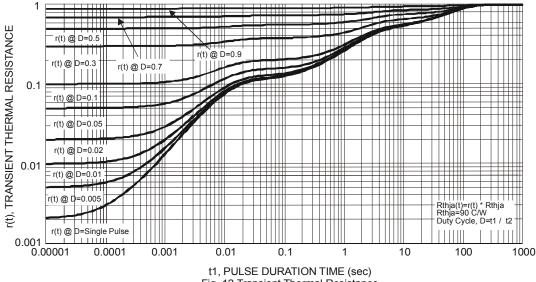
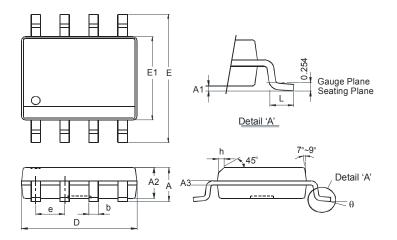


Fig. 12 Transient Thermal Resistance

Package Outline Dimensions

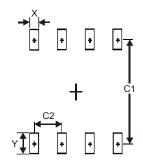
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8				
Dim	Min	Max		
Α	-	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
Α3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
Е	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h	1	0.35		
٦	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
X	0.60
Υ	1.55
C1	5.4
C2	1.27



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